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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	150
Number of Gates	36000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	176-LQFP
Supplier Device Package	176-TQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx24-1tqg176m

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2 40MX and 42MX FPGA Families

2.1 Features

The following sections list out various features of the 40MX and 42MX FPGA family devices.

2.1.1 High Capacity

- Single-Chip ASIC Alternative
- 3,000 to 54,000 System Gates
- Up to 2.5 kbits Configurable Dual-Port SRAM
- Fast Wide-Decode Circuitry
- Up to 202 User-Programmable I/O Pins

2.1.2 High Performance

- 5.6 ns Clock-to-Out
- 250 MHz Performance
- 5 ns Dual-Port SRAM Access
- 100 MHz FIFOs
- 7.5 ns 35-Bit Address Decode

2.1.3 HiRel Features

- Commercial, Industrial, Automotive, and Military Temperature Plastic Packages
- Commercial, Military Temperature, and MIL-STD-883 Ceramic Packages
- QML Certification
- Ceramic Devices Available to DSCC SMD

2.1.4 Ease of Integration

- Mixed-Voltage Operation (5.0 V or 3.3 V for core and I/Os), with PCI-Compliant I/Os
- Up to 100% Resource Utilization and 100% Pin Locking
- Deterministic, User-Controllable Timing
- Unique In-System Diagnostic and Verification Capability with Silicon Explorer II
- Low Power Consumption
- IEEE Standard 1149.1 (JTAG) Boundary Scan Testing

2.2 Product Profile

The following table gives the features of the products.

Table 1 • Product profile

Device	A40MX02	A40MX04	A42MX09	A42MX16	A42MX24	A42MX36
Capacity						
System Gates	3,000	6,000	14,000	24,000	36,000	54,000
SRAM Bits	–	–	–	–	–	2,560
Logic Modules						
Sequential	–	–	348	624	954	1,230
Combinatorial	295	547	336	608	912	1,184
Decode	–	–	–	–	24	24
Clock-to-Out	9.5 ns	9.5 ns	5.6 ns	6.1 ns	6.1 ns	6.3 ns
SRAM Modules (64x4 or 32x8)						
	–	–	–	–	–	10
Dedicated Flip-Flops	–	–	348	624	954	1,230

Table 23 • DC Specification (5.0 V PCI Signaling)¹

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
C _{IN}	Input Pin Capacitance			10	—	10	pF
C _{CLK}	CLK Pin Capacitance		5	12	—	10	pF
L _{PIN}	Pin Inductance			20	—	< 8 nH ⁴	nH

1. PCI Local Bus Specification, Version 2.1, Section 4.2.1.1.

2. Maximum rating for VCCI –0.5 V to 7.0 V

3. VIH(Min) is 2.4V for A42MX36 family. This applies only to VCCI of 5V and is not applicable to VCCI of 3.3V.

4. Dependent upon the chosen package. PCI recommends QFP and BGA packaging to reduce pin inductance and capacitance.

Table 24 • AC Specifications (5.0V PCI Signaling)*

Symbol	Parameter	Condition	PCI		MX		Units
			Min.	Max.	Min.	Max.	
ICL	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1) / 0.015$		–60	–10	mA
Slew (r)	Output Rise Slew Rate	0.4 V to 2.4 V load	1	5	1.8	2.8	V/ns
Slew (f)	Output Fall Slew Rate	2.4 V to 0.4 V load	1	5	2.8	4.3	V/ns

Note: *PCI Local Bus Specification, Version 2.1, Section 4.2.1.2.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{ja}(^\circ\text{C/W})} = \frac{150^\circ\text{C} - 70^\circ\text{C}}{(28^\circ\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

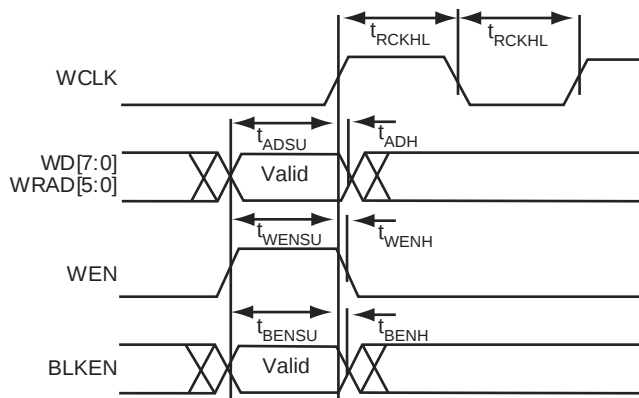
The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{jc}(^\circ\text{C/W})} = \frac{150^\circ\text{C} - 125^\circ\text{C}}{(6.3^\circ\text{C})/\text{W}} = 3.97\text{W}$$

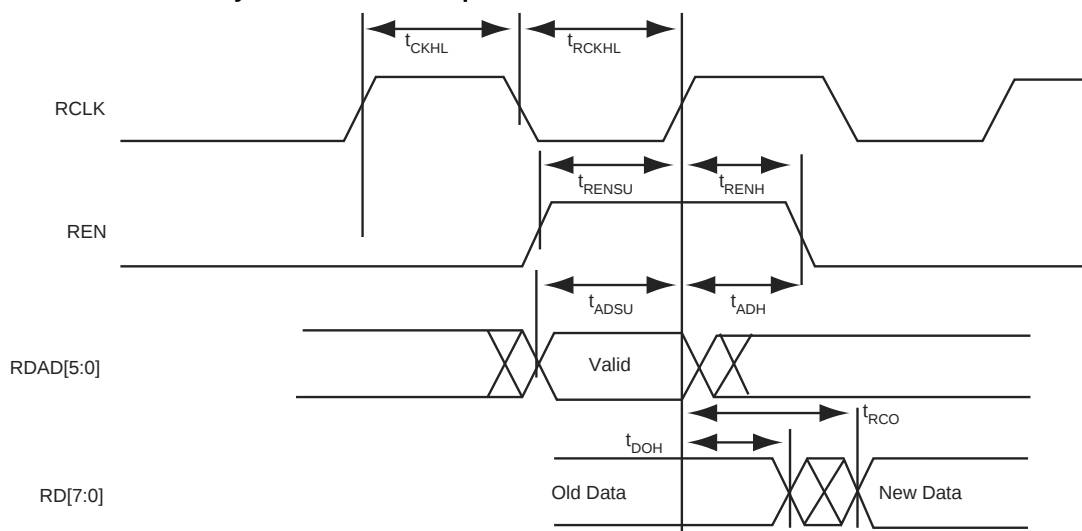
EQ 6

Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	$^\circ\text{C/W}$
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	$^\circ\text{C/W}$
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	$^\circ\text{C/W}$
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	$^\circ\text{C/W}$
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	$^\circ\text{C/W}$
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	$^\circ\text{C/W}$
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	$^\circ\text{C/W}$
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	$^\circ\text{C/W}$
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	$^\circ\text{C/W}$
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	$^\circ\text{C/W}$

Figure 30 • 42MX SRAM Write Operation

Note: Identical timing for falling edge clock

Figure 31 • 42MX SRAM Synchronous Read Operation

Note: Identical timing for falling edge clock

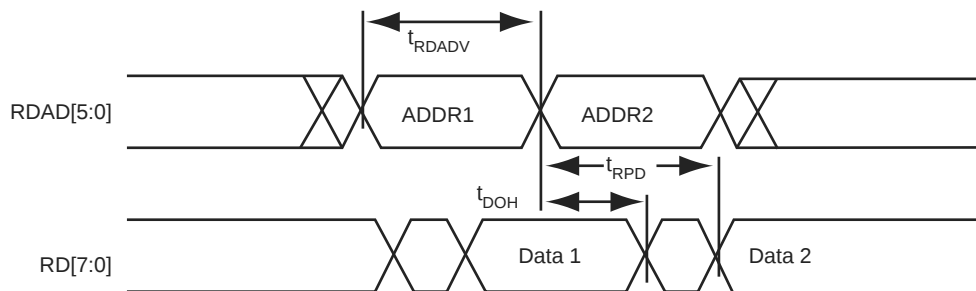
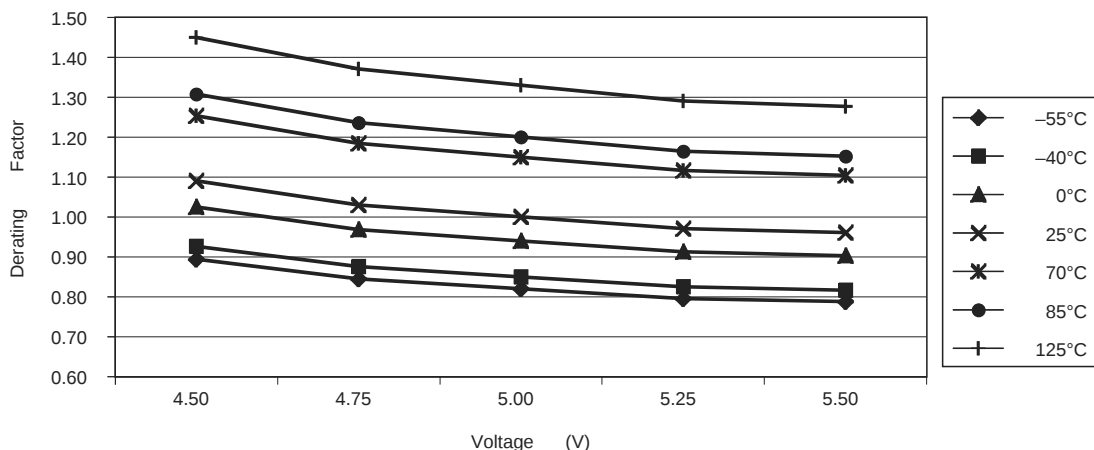
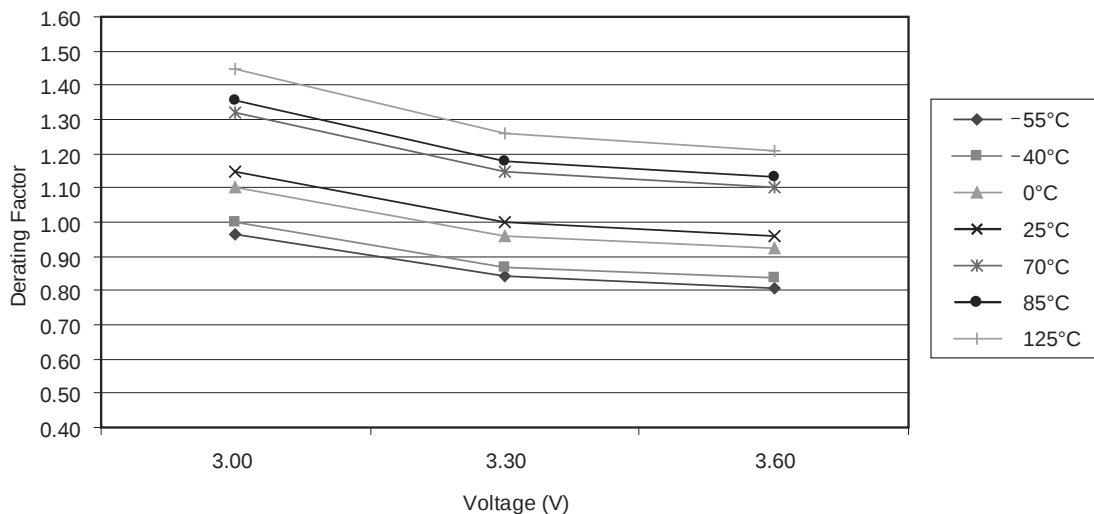
Figure 32 • 42MX SRAM Asynchronous Read Operation—Type 1 (Read Address Controlled)

Figure 35 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 30 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21

Figure 36 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 31 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{ V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59

Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation) (continued)
(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
CMOS Output Module Timing ⁴												
t _{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t _{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t _{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t _{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d _{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro
4. Delays based on 35 pF loading

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Propagation Delays												
t _{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t _{PD2}	Dual-Module Macros		2.3		3.1		3.5		4.1		5.7	ns
t _{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t _{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays ¹												
t _{RD1}	FO = 1 Routing Delay		1.2		1.6		1.8		2.1		3.0	ns
t _{RD2}	FO = 2 Routing Delay		1.9		2.2		2.5		2.9		4.1	ns
t _{RD3}	FO = 3 Routing Delay		2.4		2.8		3.2		3.7		5.2	ns
t _{RD4}	FO = 4 Routing Delay		2.9		3.4		3.9		4.5		6.3	ns
t _{RD8}	FO = 8 Routing Delay		5.0		5.8		6.6		7.8		10.9	ns
Logic Module Sequential Timing ²												
t _{SUD}	Flip-Flop (Latch) Data Input Set-Up		3.1		3.5		4.0		4.7		6.6	ns
t _{HD} ³	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up		3.1		3.5		4.0		4.7		6.6	ns

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ¹													
t _{IRD1}	FO = 1 Routing Delay		2.9		3.3		3.8		4.5		6.3		ns
t _{IRD2}	FO = 2 Routing Delay		3.6		4.2		4.8		5.6		7.8		ns
t _{IRD3}	FO = 3 Routing Delay		4.4		5.0		5.7		6.7		9.4		ns
t _{IRD4}	FO = 4 Routing Delay		5.1		5.9		6.7		7.8		11.0		ns
t _{IRD8}	FO = 8 Routing Delay		8.0		9.3		10.5		12.4		17.2		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 16 FO = 128	6.4 6.4		7.4 7.4		8.4 8.4		9.9 9.9		13.8 13.8		ns
t _{CKL}	Input HIGH to LOW	FO = 16 FO = 128	6.8 6.8		7.8 7.8		8.9 8.9		10.4 10.4		14.6 14.6		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 16 FO = 128	3.1 3.3		3.6 3.8		4.1 4.3		4.8 5.1		6.7 7.1		ns
t _{CKSW}	Maximum Skew	FO = 16 FO = 128	0.6 0.8		0.6 0.9		0.7 1.0		0.8 1.2		1.2 1.6		ns
t _P	Minimum Period	FO = 16 FO = 128	6.5 6.8		7.5 7.8		8.5 8.9		10.1 10.4		14.1 14.6		ns
f _{MAX}	Maximum Frequency	FO = 16 FO = 128	113 109		105 101		96 92		83 80		50 48		MHz
TTL Output Module Timing ⁴													
t _{DLH}	Data-to-Pad HIGH		4.7		5.4		6.1		7.2		10.0		ns
t _{DHL}	Data-to-Pad LOW		5.6		6.4		7.3		8.6		12.0		ns
t _{ENZH}	Enable Pad Z to HIGH		5.2		6.0		6.9		8.1		11.3		ns
t _{ENZL}	Enable Pad Z to LOW		6.6		7.6		8.6		10.1		14.1		ns
t _{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9		ns
t _{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7		ns
d _{TLH}	Delta LOW to HIGH		0.03		0.03		0.04		0.04		0.06		ns/pF
d _{THL}	Delta HIGH to LOW		0.04		0.04		0.05		0.06		0.08		ns/pF

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays													
t _{INYH}	Pad-to-Y HIGH			1.0		1.2		1.3		1.6		2.2	ns
t _{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7	ns
t _{INGH}	G to Y HIGH			1.3		1.4		1.6		1.9		2.7	ns
t _{INGL}	G to Y LOW			1.3		1.4		1.6		1.9		2.7	ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay			2.0		2.2		2.5		3.0		4.2	ns
t _{IRD2}	FO = 2 Routing Delay			2.3		2.5		2.9		3.4		4.7	ns
t _{IRD3}	FO = 3 Routing Delay			2.5		2.8		3.2		3.7		5.2	ns
t _{IRD4}	FO = 4 Routing Delay			2.8		3.1		3.5		4.1		5.7	ns
t _{IRD8}	FO = 8 Routing Delay			3.7		4.1		4.7		5.5		7.7	ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32		2.4		2.7		3.0		3.6		5.0	ns
		FO = 256		2.7		3.0		3.4		4.0		5.5	ns
t _{CKL}	Input HIGH to LOW	FO = 32		3.5		3.9		4.4		5.2		7.3	ns
		FO = 256		3.9		4.3		4.9		5.7		8.0	ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.2		1.4		1.5		1.8		2.5		ns
		FO = 256	1.3		1.5		1.7		2.0		2.7		ns
t _{CKSW}	Maximum Skew	FO = 32		0.3		0.3		0.4		0.5		0.6	ns
		FO = 256		0.3		0.3		0.4		0.5		0.6	ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 256	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.3		2.6		3.0		3.5		4.9		ns
		FO = 256	2.2		2.4		3.3		3.9		5.5		ns
t _P	Minimum Period	FO = 32	3.4		3.7		4.0		4.7		7.8		ns
		FO = 256	3.7		4.1		4.5		5.2		8.6		ns
f _{MAX}	Maximum Frequency	FO = 32		296		269		247		215		129	MHz
		FO = 256		268		244		224		195		117	MHz

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		1.8		2.0		2.3		2.7		3.8		ns
t _{IRD2}	FO = 2 Routing Delay		2.1		2.3		2.6		3.1		4.3		ns
t _{IRD3}	FO = 3 Routing Delay		2.3		2.5		2.9		3.4		4.8		ns
t _{IRD4}	FO = 4 Routing Delay		2.5		2.8		3.2		3.7		5.2		ns
t _{IRD8}	FO = 8 Routing Delay		3.4		3.8		4.3		5.1		7.1		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	2.6		2.9		3.3		3.9		5.4		ns
		FO = 486	2.9		3.2		3.6		4.3		5.9		ns
t _{CKL}	Input HIGH to LOW	FO = 32	3.7		4.1		4.6		5.4		7.6		ns
		FO = 486	4.3		4.7		5.4		6.3		8.8		ns
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	2.2	2.4	2.7		3.2		4.5				ns
		FO = 486	2.4	2.6	3.0		3.5		4.9				ns
t _{PWL}	Minimum Pulse Width LOW	FO = 32	2.2	2.4	2.7		3.2		4.5				ns
		FO = 486	2.4	2.6	3.0		3.5		4.9				ns
t _{CKSW}	Maximum Skew	FO = 32	0.5		0.6		0.7		0.8		1.1		ns
		FO = 486	0.5		0.6		0.7		0.8		1.1		ns
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0	0.0	0.0		0.0		0.0		0.0		ns
		FO = 486	0.0	0.0	0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.8	3.1	3.5		4.1		5.7				ns
		FO = 486	3.3	3.7	4.2		4.9		6.9				ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	4.7	5.2	5.7		6.5		10.9				ns
		FO = 486	5.1	5.7	6.2		7.1		11.9				ns

Table 43 • A42MX24 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Sequential Timing ^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output		2.1		2.0		2.3		2.7		3.7	ns
t _{GO}	Latch Gate-to-Output		3.4		1.9		2.1		2.5		3.4	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Input Module Propagation Delays												
t _{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0	ns
t _{INGO}	Input Latch Gate-to-Output		1.8		1.9		2.2		2.6		3.6	ns
t _{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t _{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Asynchronous SRAM Operations													
t _{RPD}	Asynchronous Access Time		8.1		9.0		10.2		12.0		16.8		ns
t _{RDADV}	Read Address Valid		8.8		9.8		11.1		13.0		18.2		ns
t _{ADSU}	Address/Data Set-Up Time		1.6		1.8		2.0		2.4		3.4		ns
t _{ADH}	Address/Data Hold Time		0.0		0.0		0.0		0.0		0.0		ns
t _{RENSUA}	Read Enable Set-Up to Address Valid		0.6		0.7		0.8		0.9		1.3		ns
t _{RENHA}	Read Enable Hold		3.4		3.8		4.3		5.0		7.0		ns
t _{WENSU}	Write Enable Set-Up		2.7		3.0		3.4		4.0		5.6		ns
t _{WENH}	Write Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{DOH}	Data Out Hold Time		1.2		1.3		1.5		1.8		2.5		ns
Input Module Propagation Delays													
t _{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1		ns
t _{INGO}	Input Latch Gate-to-Output		1.4		1.6		1.8		2.1		2.9		ns
t _{INH}	Input Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t _{INSU}	Input Latch Set-Up		0.5		0.5		0.6		0.7		1.0		ns
t _{ILA}	Latch Active Pulse Width		4.7		5.2		5.9		6.9		9.7		ns
Input Module Predicted Routing Delays ²													
t _{IRD1}	FO = 1 Routing Delay		2.0		2.2		2.5		2.9		4.1		ns
t _{IRD2}	FO = 2 Routing Delay		2.3		2.6		2.9		3.4		4.8		ns
t _{IRD3}	FO = 3 Routing Delay		2.6		2.9		3.3		3.9		5.5		ns
t _{IRD4}	FO = 4 Routing Delay		3.0		3.3		3.8		4.4		6.2		ns
t _{IRD8}	FO = 8 Routing Delay		4.3		4.8		5.5		6.4		9.0		ns
Global Clock Network													
t _{CKH}	Input LOW to HIGH	FO = 32	2.7	3.0	3.4	4.0	5.6	ns					
		FO = 635	3.0	3.3	3.8	4.4	6.2	ns					
t _{CKL}	Input HIGH to LOW	FO = 32	3.8	4.2	4.8	5.6	7.8	ns					
		FO = 635	4.9	5.4	6.1	7.2	10.1	ns					
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	1.8	2.0	2.2	2.6	3.6	ns					
		FO = 635	2.0	2.2	2.5	2.9	4.1	ns					
t _{PWL}	Minimum Pulse Width LOW	FO = 32	1.8	2.0	2.2	2.6	3.6	ns					
		FO = 635	2.0	2.2	2.5	2.9	4.1	ns					
t _{CKSW}	Maximum Skew	FO = 32	0.8	0.8	0.9	1.0	1.4	ns					
		FO = 635	0.8	0.8	0.9	1.0	1.4	ns					

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{RD5}	FO = 8 Routing Delay		4.6		5.2		5.8		6.9		9.6	ns
t _{RDD}	Decode-to-Output Routing Delay		0.5		0.5		0.6		0.7		1.0	ns
Logic Module Sequential Timing ^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{GO}	Latch Gate-to-Output		1.8		2.0		2.3		2.7		3.7	ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output		2.2		2.4		2.7		3.2		4.5	ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	1.0		1.1		1.2		1.4		2.0		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Synchronous SRAM Operations												
t _{RC}	Read Cycle Time	9.5		10.5		11.9		14.0		19.6		ns
t _{WC}	Write Cycle Time	9.5		10.5		11.9		14.0		19.6		ns
t _{RCKHL}	Clock HIGH/LOW Time	4.8		5.3		6.0		7.0		9.8		ns
t _{RCO}	Data Valid After Clock HIGH/LOW	4.8		5.3		6.0		7.0		9.8		ns
t _{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 48 • PL68

PL68		
Pin Number	A40MX02 Function	A40MX04 Function
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	GND	GND
67	I/O	I/O
68	I/O	I/O

Figure 40 • PL84

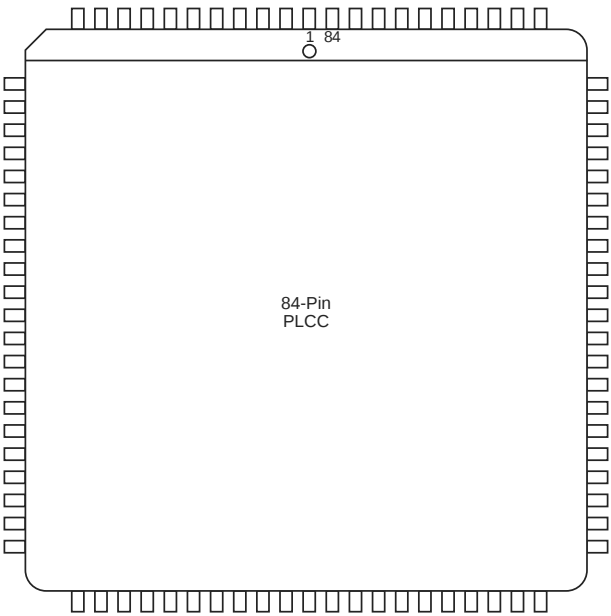


Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
1	I/O	I/O	I/O	I/O
2	I/O	CLKB, I/O	CLKB, I/O	CLKB, I/O
3	I/O	I/O	I/O	I/O
4	VCC	PRB, I/O	PRB, I/O	PRB, I/O
5	I/O	I/O	I/O	WD, I/O
6	I/O	GND	GND	GND
7	I/O	I/O	I/O	I/O
8	I/O	I/O	I/O	WD, I/O
9	I/O	I/O	I/O	WD, I/O

Figure 42 • PQ144

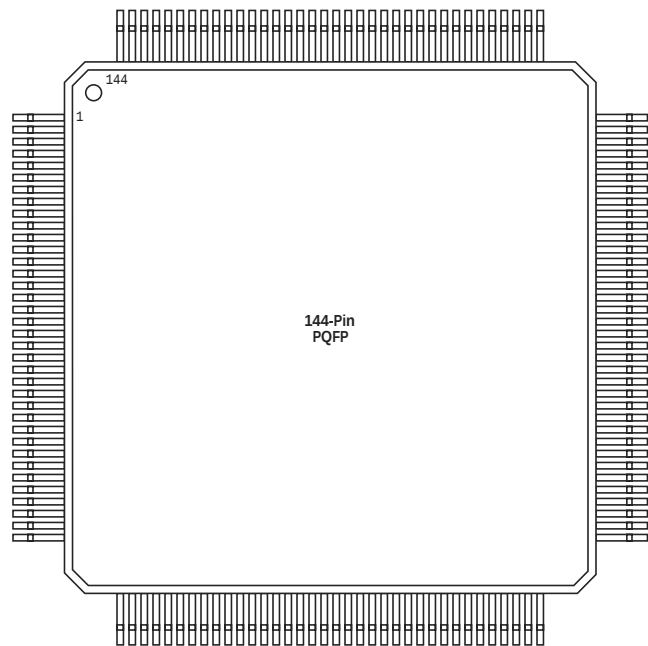


Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Table 55 • VQ80

VQ80		
Pin Number	A40MX02 Function	A40MX04 Function
13	VCC	VCC
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	NC	I/O
18	NC	I/O
19	NC	I/O
20	VCC	VCC
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	GND	GND
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	VCC	VCC
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	NC	I/O
42	NC	I/O
43	NC	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	GND	GND
48	I/O	I/O

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
J9	GND
J10	GND
J11	GND
J12	GND
J17	VCCA
J18	I/O
J19	I/O
J20	I/O
K1	I/O
K2	I/O
K3	I/O
K4	VCCI
K9	GND
K10	GND
K11	GND
K12	GND
K17	I/O
K18	VCCA
K19	VCCA
K20	LP
L1	I/O
L2	I/O
L3	VCCA
L4	VCCA
L9	GND
L10	GND
L11	GND
L12	GND
L17	VCCI
L18	I/O
L19	I/O
L20	TCK, I/O
M1	I/O
M2	I/O
M3	I/O
M4	VCCI
M9	GND

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
N10	I/O
M10	I/O
N11	I/O
L10	I/O
M11	I/O
N12	SDO
M12	I/O
L11	I/O
N13	I/O
M13	I/O
K11	I/O
L12	I/O
L13	I/O
K13	I/O
H10	I/O
J12	I/O
J13	I/O
H11	I/O
H12	I/O
H13	VKS
G13	VPP